how to understand spectral luminescence from thin film absorbers, absorber layer sequences and complete solar cells

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- basics of steady state luminescence (Planck's generalized law)
- application to experimental results and requirements for evaluation

o influence of temperature, spectral absorption, quasi-Fermi levels

o lateral inhomogeneous absorbers

- o carrier depth profiles and depth dependent parameters
- numerical modeling of spectral pl
- interpretation of results (including multilayer optics) with re-absorption of luminescence photons, excess carrier depth profiles, lateral inhomogeneities...

no summary



how to understand spectral luminescence from thin film absorbers, absorber layer sequences and complete solar cells

method applied to

- a-Si:H/c-Si heterodiodes (-> optimization of interface)
- c-Si absorbers (-> passivation)
- c-Si reference absorbers in 3rd generation approaches
- polycrystalline semiconductors / diodes (CdTe, Cu(Ga,In)Se₂, Cu(Ga,In)S₂.)
- thin polycristalline injection diodes
- diodes of anorganic matrices with organic dyes





cross section of a $Cu(In_{0.7}Ga_{0.3})Se_2$ thin film on Mo coated glass substrate









photoluminescence for determination of effects of manipulation of coupling solar light into absorbers





photoluminescence for determination of effects of manipulation of coupling solar light into absorbers



splitting of quasi-Fermi levels (ε_{Fn} - ε_{Fp}) via Planck's generalized law

photon flux from matter

, µ_{phot}

 $\Gamma(\omega) = \epsilon(\omega) \omega^2 \{ \exp \left[(\hbar \omega - \mu_{phot}) / kT \right] - 1 \}^{-1}$

dΩ

Γ(ω)

 $\epsilon(\omega)$ - spectral emissivity μ_{phot} - chemical potential of the photon field

coupling of Bosons (μ_{phot}) and Fermions ($\mu_{n,p}$) via rate equations of absorption and emission (spont. & stim.) in an electronic 2-level/band system

 $\mu_{phot} = \mu_{n,p} = (\epsilon_{Fn} - \epsilon_{Fp}) \ge v_{oc}$

(necessary condition in thermal non-equilibrium: $\tau_{intraband}$ (momentum and energy relax.) << $\tau_{interband}$ (recomb.) (maximum entropy distribution function -> temperature)

integration over entire volume of matter $\int \Gamma(\omega) d\Omega$ including wave optics (propagation, scattering, absorption, reflexion, photon recycling,..)





steady state conditions and fast intraband relaxation

solar photons reflect sun surface temperature 6000 K

 \rightarrow provide for "hot" carriers





maximum achieavable chemical potential of electron hole-ensemble

steady state balance of photon fluxes from sun (T_{sun}) absorbed by system at (T_{rec}) with chemical potential of electron hole ensemble $\mu_{n,p}$





maximum achieavable chemical potential of electron hole-ensemble

steady state balance of photon fluxes from sun (T_{sun}) absorbed by system at (T_{rec}) with chemical potential of electron hole ensemble $\mu_{n,p}$





chemical potential of photon field and of electron hole-ensemble





COUPLING of BOSONS (PHOTONS) and FERMIONS (ELECTRONS-HOLES) in an ELECTRONIC TWO-LEVEL/BAND SYSTEM

o optical transitions $\hbar \omega = \epsilon_2 - \epsilon_1 = \epsilon_g$

absorption, stimulated & spontaneous emission $B_{12} n(\epsilon_1) p(\epsilon_2) u_{phot}(\hbar \omega) 4\pi = B_{21} n(\epsilon_2) p(\epsilon_1) u_{phot}(\hbar \omega) 4\pi + A_{21} n(\epsilon_2) p(\epsilon_1)$ $(B_{12} = B_{21})$

o level occupation by Fermi-/quasi-Fermi-statistics:

$$\begin{split} n(\epsilon_2) &= D(\epsilon_2) \ f_n^*(\epsilon_2) \ = D(\epsilon_2) \ \{ exp[(\epsilon_2 - \epsilon_{Fn})/kT] + 1 \}^{-1} \quad (\text{conduction band}) \\ p(\epsilon_1) &= D(\epsilon_1) \ f_p^*(\epsilon_1) \ = D(\epsilon_1) \ \{ exp[\epsilon_{Fp} - \epsilon_1)/kT] + 1 \}^{-1} \quad (\text{valence band}) \end{split}$$

and via charge neutrality	$\mathbf{n}(\boldsymbol{\varepsilon}_1) = \mathbf{D}(\boldsymbol{\varepsilon}_1)[1 - \mathbf{f}_p^*(\boldsymbol{\varepsilon}_1)]$	(valence band)
	$p(\varepsilon_2) = D(\varepsilon_2)[1-f_n^*(\varepsilon_2)]$	(conduction band)







messages included in the spectral pl-yield (Planck's generalized law)





chemical potential of the electron-hole-ensemble μ_{np} via Bose-Term of Planck's Generalized Law





contribution to photon flux from many volume elements



including wave optics (propagation, scattering, absorption, reflection, photon recycling,..)

multilayer optics for the formulation of total photon flux to detector



formalization of luminescence photon propagation (plane wave approach)







comparison of experimental and calculated pl-yields













calibrated room temperature luminescence (AM1 equivalent excitation) versus confocally resolved luminescence





problems by averaging photon fluxes



lateral pattern of photon fluxes with different chemical potentials

avereging of photon individual fluxes $\sum \mathbf{Y}_{\text{pl}\ ,i}$

→ extraction of quasi Fermi level splitting

$$\begin{split} & \textbf{E}_{Fn}\textbf{-}\textbf{E}_{Fp} \sim \textbf{kT} \ln \left(\sum Y_{pl,i} \right) \\ & \textbf{averaging of individual chemical potentials} \\ & \textbf{E}_{Fn}\textbf{-}\textbf{E}_{Fp} \sim \textbf{kT} \sum \ln \left(Y_{pl,i} \right)) \end{split}$$



problems by averaging photon fluxes



lateral pattern of photon fluxes with different chemical potentials



analyze distribution function (FWHM)



problems by averaging photon fluxes



lateral pattern of photon fluxes with different chemical potentials

avereging of photon individual fluxes

 $\sum Y_{pl,i}$

- → extraction of quasi Fermi level splitting
 - $E_{Fn}-E_{Fp} \sim kT \ln \left(\sum Y_{pl,i}\right)$

avereging of individual chemical potentials

 $E_{Fn}-E_{Fp} \sim kT \sum ln (Y_{pl,i})$





problems by averaging photon fluxes



lateral pattern of photon fluxes with different chemical potentials

avereging of photon individual fluxes

 $\sum Y_{pl,i}$ \rightarrow extraction of quasi Fermi level splitting

$$E_{Fn}-E_{Fp} \sim kT \ln \left(\sum Y_{pl,i}\right)$$

avereging of individual chemical potentials

$$E_{Fn}-E_{Fp} \sim kT \sum ln (Y_{pl,i})$$





spectral absorption coefficient of $Cu(In_{0.7}Ga_{0.3})Se_2$ extracted from laterally highly resolved (1 µm) white light transmission



lateral pattern of white light transmitted photons (variation of (αd))

$$A_{average}(\omega) = \sum_{i} \left(1 - \exp[-\alpha_i d_i] \right)$$

average absorption coefficient ??

$$\alpha_{average}(\omega) = -\frac{1}{d} \ln \left(1 - A_{average}(\omega) \right)$$



critical / inappropriate averaging of relevant magnitudes









dependence of spectral luminescence signal on carrier depth profile





numerical modelling for examination of influence of carrier depth profile on spectral pl





excess carrier depth profiles and according spectral pl-yields (plane wave approach)



excess carrier depth profiles and according spectral pl-yields (plane wave approach)



carrier depth profiles and according spectral luminescence yields





determination of quasi-Fermi level splitting

excess carrier depth profiles



 $(E_{Fn}-E_{Fp})$ calculated from carrier profiles versus $(E_{Fn}-E_{Fp})$ from pl-evaluation



for surface recombination velocities $S \le 3x10^3$ cm/s \rightarrow departure of (E_{Fn}-E_{Fp}) by pl-evaluation from exact value < 1 meV



excess carrier depth profiles and according spectral pl-yields





interference pattern from luminescence (centers distributed across depth) and from spectral transmission





interference patterns from spectral luminescence versus those from spectral transmission

pl emission centers







lateral, inhomogeneous with "percolative" transmission (low concentration of absorbing centers (dyes))

lateral distribution of absorption centers



ξ_i = 1 0

1







NO summary



- → don't mix magnitudes (luminescence, absorption, etc.) that superimpose non-linearly !!
- → front side / light entrance = position of hetero junction, for decent front layer passivation (E_{Fn}-E_{Fp}) → e Voc;
- → departure of high energy pl-photon fluxes from ideal Bose-behavior indicates
 by positive curvature → shift of maximum carrier concentration deep in the absorber
 by negative curvature → depth dependent optoelectronic properties of absorber (gradient in band gap, life time etc.)



luminescence as tool for analyses of quality of photo excited states in matter



